



XA-10014
PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

Kenzaburo SUZUKI

Appln. No.: 10/742,894

Group Art Unit: 2851

Filed: December 23, 2003

Examiner: W. Perkey

For: ZOOM LENS SYSTEM

* * *

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 C.F.R. § 1.56, and without any assertion as to materiality or prior art effect, the documents listed on the attached Form PTO-1449 are hereby cited.

Document AA on the attached List corresponds to Documents AJ and AK of Form PTO-1449 filed with the Information Disclosure Statement filed May 26, 2004.

Document AB on the attached List corresponds to Document AL of Form PTO-1449 filed with the Information Disclosure Statement filed May 26, 2004.

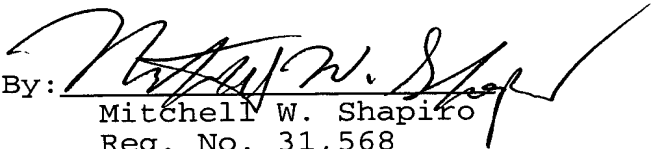
Document AP on the attached List was cited in the specification, on pages 6 and 16, and its relevance is indicated therein. An English translation is also attached.

Respectfully submitted,

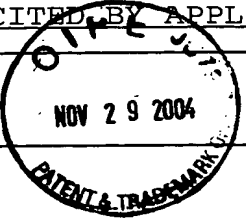
MWS:sjk

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By:


Mitchell W. Shapiro
Reg. No. 31,568

November 29, 2004

FORM PTO-1449				Atty. Docket No. XA-10014		Appln. No. 10/742,894	
<u>LIST OF DOCUMENTS CITED BY APPLICANT</u>				Applicant Kenzaburo SUZUKI			
							
				Filing Date December 23, 2003		Group 2851	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
	AA	6,081,389	6/27/00	Takayama et al.	359	680	
	AB	2003/0076591	4/24/03	Ohmori et al.	359	566	
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
	AJ						
	AK						
	AL						
	AM						
	AN						
	AO						
OTHER (including author, title, date, pertinent pages, etc.)							
	AP	"Introduction to Diffractive Optical Elements," Supervised by Optical Design Study Group in the Optical Society of Japan, OPTRONICS, 1997 (with English translation).					
	AQ						
	AR						
Examiner				Date Considered			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							